Silicon tracking DAQ

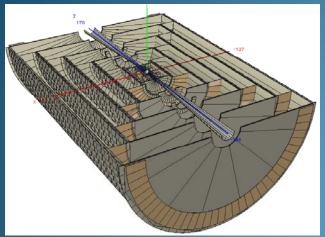
Still preliminary thoughts on all DAQ parts but the first one (FEE)

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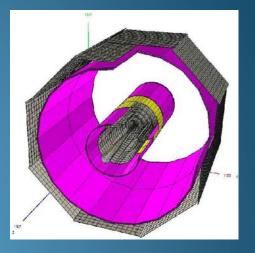
This work is performed within the SiLC R&D collaboration and with partial support from E.U. I3-FP6 EUDET project support

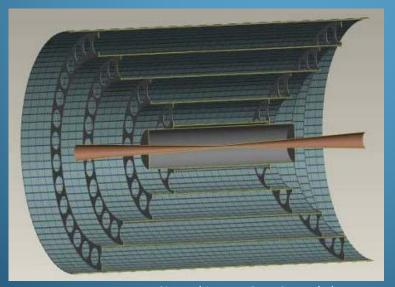
ILC ECFA Workshop at Warsaw, June 11 2008

PRELIMINARY WARNING



All what is presented here apply to any Si tracking system for ILC, made with strip sensors and representing a few 10**6 channels to be read out and processed





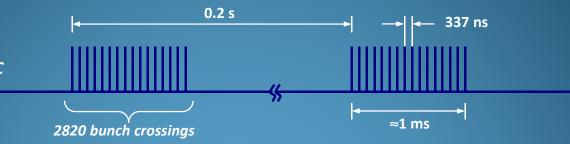
Not applied (yet)! to a all pixel large area Si tracking (30 x 10**9 pixel channels)

Si Tracking DAQ, ILC Workshop, Warsaw June 11, 2008 (A. Savoy-Navarro)



THE TIME WE ARE GIVEN....

Bunch structure at the ILC



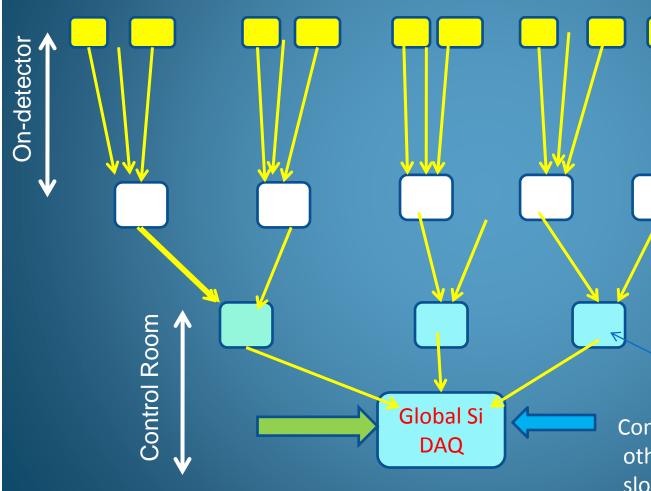
HOW DO WE USE IT? numerical oscilloscopy storing zero suppressing **THEN:** A/D conversion power cycling calibrating (?) Si Tracking DAQ, ILC Workshop, Warsaw

June 11, 2008 (A. Savoy-Navarro)

TOPICS

- SILICON TRACKING DAQ: 3 FLOORS
- FLOOR 1: on the chip
- FLOOR 2: on the detector sides
- FLOOR 3: in the Control Room
- Towards developing this DAQ architecture: the first steps

Si Tracking DAQ architecture into 3 floors



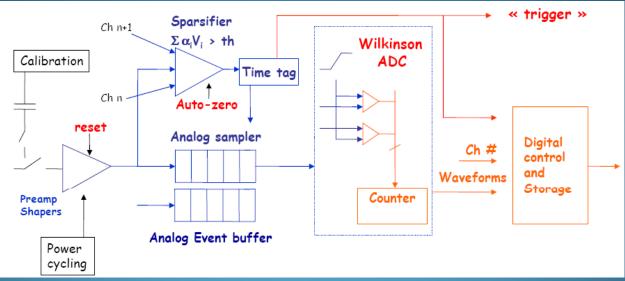
F 1: chip on sensor, Full read out chain in a single chip (A/D, zero suppress, multiplex, F.T.

F2: on detector sides, Daisy chaining chips information from chips, buffering, preprocess, interface/outside world

F3: in control room, processing /azimuthal sector, trk reconstruct.

Combine with Information from other sub-detectors, handling slow control for all Si TrK system

Floor 1: FE chip on elementary module



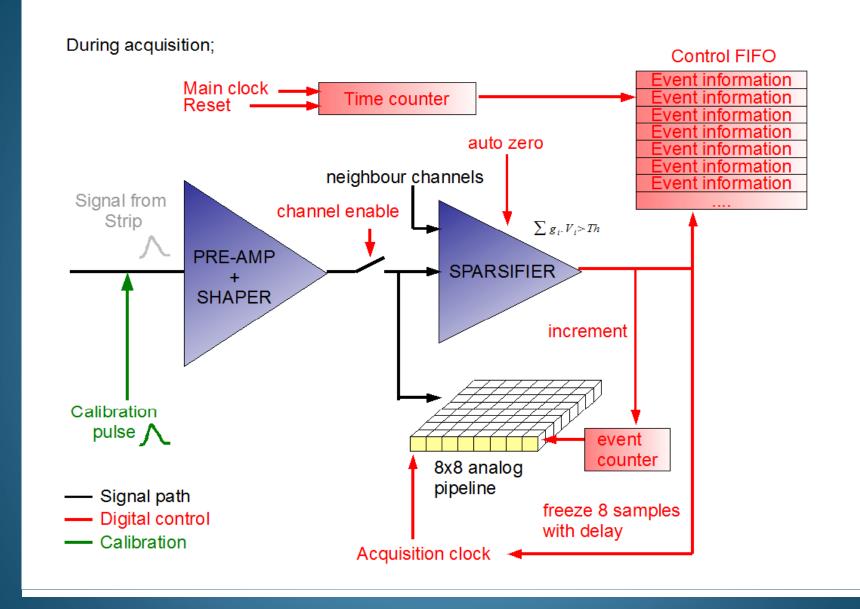
Full readout chain integration in a single chip, 512 or 1024 ch in 90nmCMOS

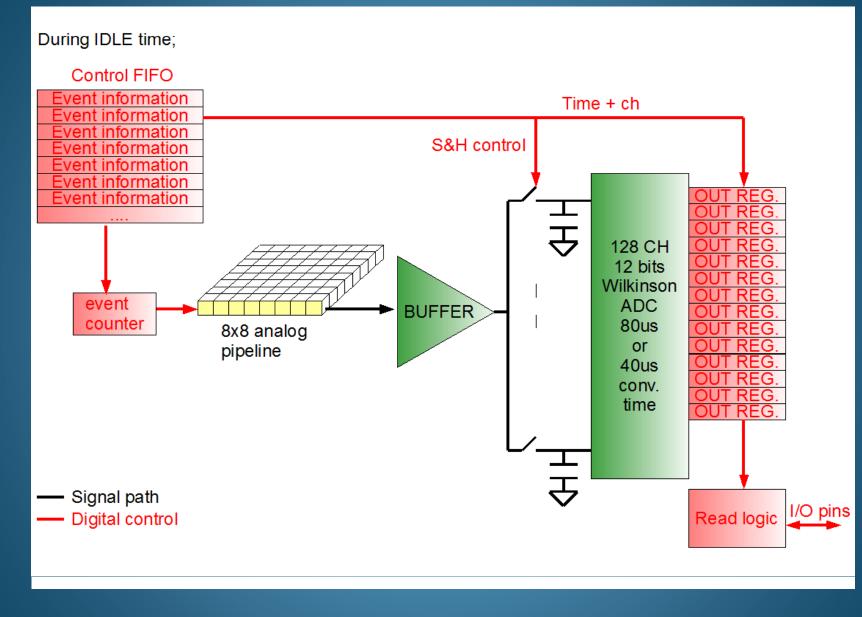
- Preamp-shaper
- Sparsification Trigger decision on analogue sums (3 or 5 adjacent channels)
- Sampling 8-deep sampling analogue pipe-line
- Analogue event buffering: Occupancy: 8-16 deep event buffer
- On-chip digitization 12-bit ADC (highly multpiplexed)
- Buffering and pre-processing: Centroids, $\chi 2$ fits, lossless compression & error codes
- Calibration and calibration management
- -Power switching (ILC duty cycle)

--Digital control: operation fully programmable (all settings of chip operations), fault tolerance, robustness, reliability, flexibility.

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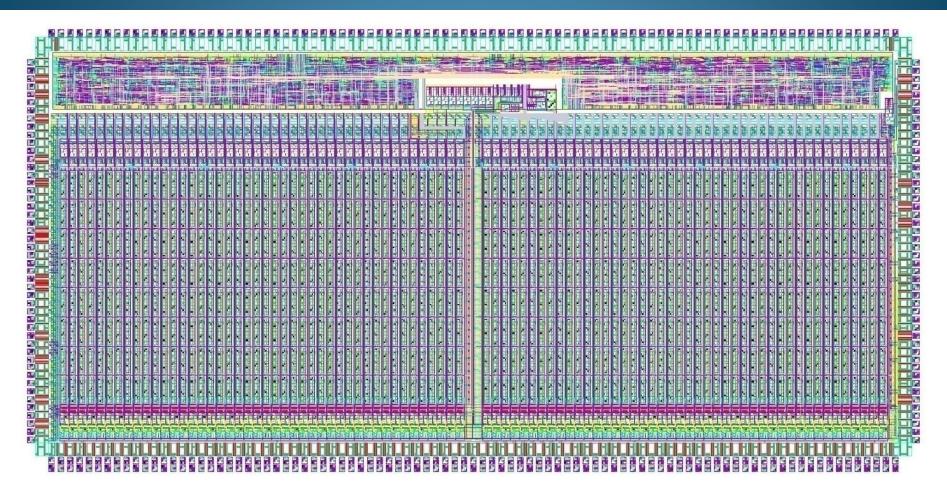
Operations during acquisition Operations on IDLE time Output registers block Output registers structure Writing data Reading data Output logic







THE ELEMENTARY and CRUCIAL PIECE in DAQ Silicon Tracking, does it all (almost!!) University of Barcelona and LPNHE-UPMC/IN2P3-CNRS 91 I/O digital (power supplies, clock, tests,serial I/O)



88 strip inputs +2 power suplies + one ground THE PRESENT CHIP PROTOTYPE SiTR_130-88 includes all the feature (sent to foundry)

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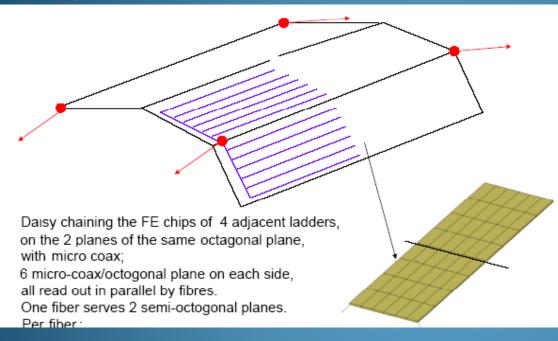
FEE is full custom and DSM CMOS technology (now 130nm soon 90 nm will be tried)

Crucial and novel solution for direct interconnection chip on detector now bump bonding for strips (as for pixels) very soon for both 3D vertical interconnect

For the rest of the DAQ: look AMAP for solutions available on the market

FLOOR 2: FE-on detector edges, interface detector with external world

Example



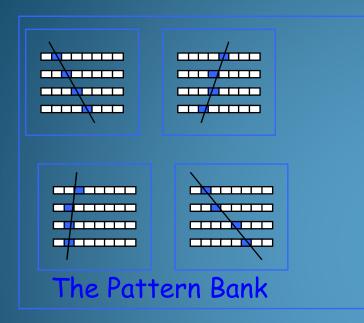
Cabling:

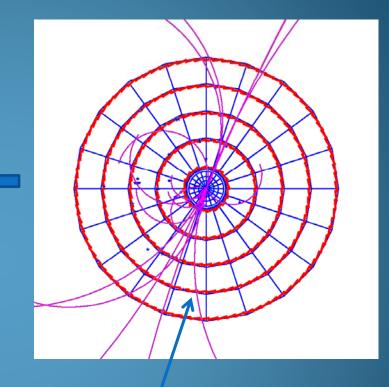
Floor 1 to Floor 2: microcoax Floor 2 to Floor 3: digital fibers

Number of issues related to cabling: Follow industrial advances High rates and high speed, reliability, fault tolerance, robustness Common for all sub detectors

Each red points = buffer + pre-processing 2 (re-ordering & compressing data), transceiver (digital fiber to external world = Control Room) Sends predigested data at CR and get slow control and distributes it on detector

Floor 3: Si TRK DAQ in the C.R., integration phase



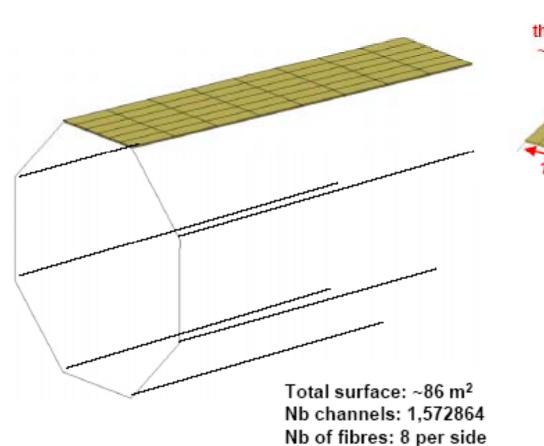


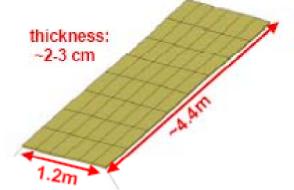
REAL TIME PROCESSING at floor3:

organize the processors for instance regrouping F2 elements belonging to a same azimuthal sector and perform tracking, a la CDF or FTK=FastTrack Finding (LHC). SLOW CONTROL: synchronisation (Clock), power supplies, calibration signal, operation Parameters settings

COMBINE information from SiTracking wih other SUBDTECTORS

Just an educated guess example





# ladders/octagone	96
# sensors/octagone	288
# channels/octagone	196608
# µchips/octagone	192
# µcoax/octagone	192
# fibres/octagone	2
# µchips/fibre	96
# channels /fibre	98304

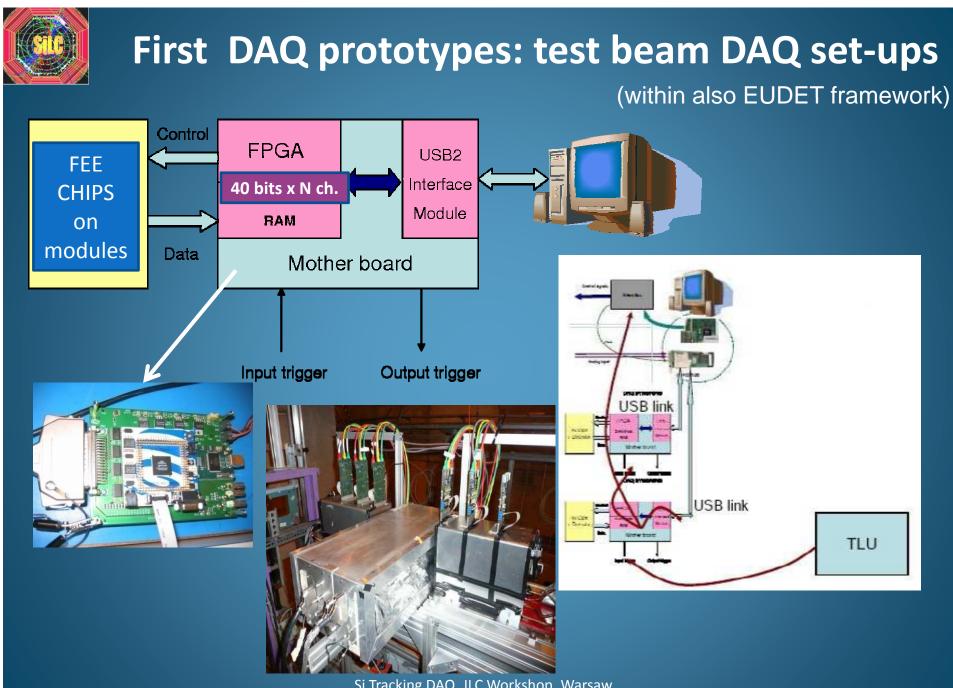
Outer Silicon tracking layer : false double sided sensors

Cabling and data flow transmission

Data Flow transmission: presently foreseen to use micro-coax Cables of typically 1" diameter , 300 mW power dissipation at 1 GHz, can be power cycled. Kapton cables also under Consideration At a later stage: to transmit data from the edge of the detector to the outside, 6 GHz SCM digital optic links are presently considered

Related to this topic the data processing at all levels as described are a feature of our DAQ architecture. DSP mounted as multichip modules would represent a very small amount of material (especially at the edge of the detector) and dissipate very little. We are starting to think on a real time track processing scenario

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Concluding remarks

- The first level of the Silicon DAQ in a ILC and micro strips detector based scenario is well in hand and is a crucial piece in the Si DAQ
- The strategy considered for the DAQ Si tracking upper levels is based on a early stage reconstruction of track segments, then full tracking
- Combining and thus uniformization with other sub detectors & global DAQ becomes a condition sine qua non to progress in the right direction
- Close contact with Industries are essential this field too in order to avoid useless and expensive R&D work and makes system becoming soon obsolete.
- Highly performing FEE with full readout capability, fault tolerance, fully programmable, high degree of processing already at early stage in the DAQ chain (with electronics wrt detector architecture)
- Last but not least: Cabling and data transmission / data processing
- Here also test beams are essential tool to develop DAQ

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